

Thomas Kehagias

Current Position

Professor of Condensed Matter and Materials Physics (2016-), School of Physics, AUTH.
Director of the Electron Microscopy and Structural Characterization of Materials Laboratory (2023-).

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Identifiers

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Google Scholar: <https://scholar.google.com/citations?user=LwCLndsAAAAJ&hl=el&oi=sra>

Publications & Bibliometric Data

h-index = 30 (Scopus), 156 publications in peer reviewed international journals, 3000 citations (Scopus), 2 chapters in international scientific books, 7 highlight, featured, or invited papers in peer-reviewed journals, guest editor of 3 international scientific volumes, member of the editorial board of one international journal, reviewer in 21 journals, author of educational material.

Research Expertise

Main Topic: Characterization of the structural properties of condensed matter by Transmission Electron Microscopy techniques (TEM-HRTEM-STEM).

Particular interests: Structural characterization of semiconductors on various substrates for photonic and micro-/nanoelectronics applications. Interfaces and mechanical properties of 0D, 1D and 2D nanostructures, i.e., quantum dots, nanowires and quantum wells.

Determination of the chemical composition of nanostructures by energy dispersive X-ray spectroscopy (EDS) and STEM high-angle annular dark field (HAADF) imaging. Spintronic thin films and magnetic multilayers. Metallic nanoparticles in amorphous matrices. Composite materials.